**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Applicant	:	Bogdan C. Maglich
App. No.	:	09/883,851
Filed	:	June 18, 2001
For	:	METHOD AND APPARATUS FOR NEUTRON MICROSCOPY WITH STOICHIOMETRIC IMAGING
Examiner	:	Jack W. Keith
Group Art Unit	:	3641

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing one (1) reference that is also enclosed.

This Supplemental Information Disclosure Statement is being filed after the mailing date of a final action under 37 C.F.R. § 1.113. This Statement is accompanied by the fee set forth in 37 C.F.R. § 1.17(p). The Commissioner is hereby authorized to charge any additional fees which may be required or to credit any overpayment to Account No. 11-1410. A certification under 37 C.F.R. § 1.97(e) is set forth below.

**CERTIFICATION UNDER 37 C.F.R. § 1.97(e)(2)**

I hereby certify that no item of information contained in this Statement was cited in a communication from a foreign Patent Office in a counterpart foreign application, and, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 C.F.R. § 1.56(c) more than 3 months prior to the filing of this Supplemental Information Disclosure Statement.

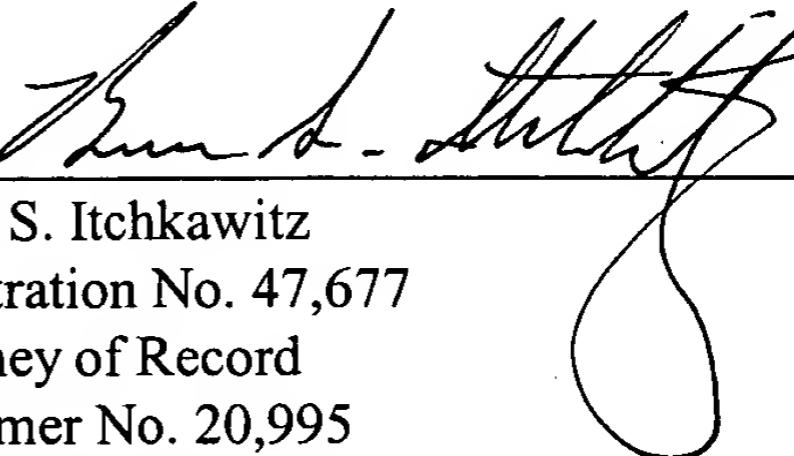
Appl. No. : 09/883,851  
Filed : June 18, 2001

Docket No. HIENER.1CPC1CP  
Customer No. 20,995

Respectfully submitted,

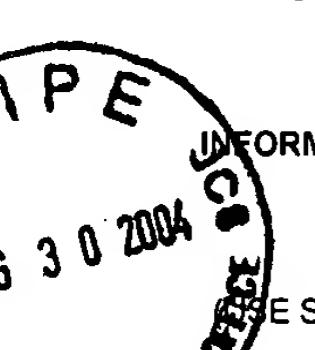
KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 8/26/04

By: 

Bruce S. Itchkawitz  
Registration No. 47,677  
Attorney of Record  
Customer No. 20,995  
(949) 760-0404

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FORM PTO-1449  	U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. HIENER.1CPC1CP	APPLICATION NO. 09/883,851
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Bogdan C. Maglich	
(USE SEVERAL SHEETS IF NECESSARY)		FILING DATE June 18, 2001	GROUP 3641

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	Beyerle, Albert, et al., <i>Design of an associated particle imaging system</i> , <u>Nuclear Instruments and Methods in Physics</u>
	Research A299 (1990), pp. 458-462.

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EXAMINER	DATE CONSIDERED
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